FORM PTO-1449		US Dept. of Commerce Patent and Trademark Office		ATTORNEY DOCKET NO.		SERIAL NO.			
			Patent and 1 rat	Temark Office	ATMI-537-CIP	4	10/632,009		
						(2000 B)			
INFORMATION DISCLOSURE STATEMENT				TEMENT	Chongying Xu, et al. FILING DATE FULL 21 2003 GROUP Lub 21 2003				
(use several sheets if necessary)				агу)	FILING DATE	. OK. CO.	GROUP		
			July 31, 2003	DRAM	2818				
U.S. PATENT DOCUMENTS									
EXAMINER .			PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DA	
PO		AA	5,840,897	11/24/1998	Kirlin, et al.	·	SUBCLASS	IF ATTROTA	LATE
*		AB	5,453,494	9/26/1995	Kirlin, et al.				
	_	AC	6,110,529	8/29/2000	Gardiner, et al.				
		AD	5,820,664	3/31/1995	Gardiner, et al.				
	-	AE	5,225,561	9/12/1990	Kirlin, et al.				
	├	AF	5,789,027	8/4/1998	Watkins, et al.				
	┢	AG	6,576,345 B1	6/10/2003	Van Cleemput, et al.				
	ļ.	AH	5,211,342A	5/18/1993	Hoy, et al.				
	H -	Al	6,207,522B1	3/27/2001	Hunt, et al.				
P	<u> </u>	AJ	10/632,009	· .	Chongying Xu, et al.			11/25/2002	
1 2		<u> </u>		FOREIC	ON PATENT DOCUMENTS				
			DOCUMENT	PUBLICATION				TRANSLAT	
	•		NUMBER	DATE	COUNTRY	CLASS	SUBCLAS S	YES	NO
								X `	
.								(abstract only)	
		<u></u>	OTHER DOCUM	AENTS (Includ	ing Author, Title, Journal-D	ate, Page N	umber, Etc.)		
PP		AK	Brian N. Hansen 1992, 4, 749-752	, et al., "Supercr	itical Fluid Transport-Chemica	l Depositio	n of Films" C	hemical Mater	rials,
817	,	AL	Jason M. Blackb	urn, et al., "Dep	osition of Conformal Copper a	nd Nickel F	ilms from Sup	percritical Car	bon
	Dioxide" Science, Vol 294, October 5, 2001, pgs. 141-145								
AM C.Y. Xu, et al., "Supercritical Carbon Dioxide Assisted Aerosolization for Thin Film Deposition, Fin Powder Generation, and drug delivery", Green Chemistry, Editors: Anastas, Paul T., et al. Oxford									
"	University Press, Oxford, UK, pgs. 312-335.								
Continue on Page									
EXAMINER DATE CONSIDERED									
PHUCT DANG				11/19/2004					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through									
citation	citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.								

PTO/SE/08A (01-04)
Approved for use through 07/31/2006. OMB 0651-0031
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Sheet 1 of 1

U.S. PATENT DOCUMENTS					
Examiner 'Initials*	Cite No.	Document Number	Publication Date MM-DD-YYYY	Issue Date MM-DD-YYYY	Name of Patentee or Applicant of Clied Document
P.D		US-6,403,663		06-11-2002	DeSimone et al.
PP		US-6,653,236		11-25-2003	Wai et al.
PD		US-6,576,345		06-10-2003	Van Cleemput et al.
		US-			,
		US-			/
		US-			
		US-		.•	
		US-			
		US-			
		US-			
1		US-			
		US-			

				_
Examiner	9114 6 5 01-16	Date	10-10-100	_
signature	I HUCT, DANG	Considered	02/03/03	•

^{*}Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

¹ All the foreign patents and publications that are not written in English language are accompanied by their respective English abstracts, which constitute concise explanation of relevance of the non-English patents and publications that satisfy the requirements of 37 C.F.R.,§1.98(a)(3)(i), according to MPEP 609 III A(3).